## Applicant(s)/Patent Under Application/Control No. Reexamination 09/897,257 KLEIN, JOHN T. Notice of References Lited Art Unit Examiner Page 1 of 1 2653 Christopher R. Magee **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 08-1986 Edwards et al. 414/592 US-4,604,024,. Α US-4,754,445 06-1988 Young et al. 369/30.86 В С US-5,158,331 10-1992 Wesselski et al. 294/94 US-5,195,794 03-1993 294/94 D Hummel et al. US-5,503,446 04-1996 Е De Jong, Dirk 294/94 F US-5,505,509 04-1996 Vance, Dean W. 294/16 G US-5,542,526 08-1996 Wurgler, Winston A. 294/93 Н US-5,934,865 08-1999 Meadows, John W. 414/796.9 US-6,111,847 08-2000 Assadian, Hamid R. 369/30.55 US-6,220,640 04-2001 Jensen et al. 294/93 J US-2002/0009022 A1 01-2002 Britz et al. Κ 369/30.34 US-L US-FOREIGN PATENT DOCUMENTS Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν JP 01104532 A 04-1989 SUZUKI, MICHIHIKO Japan B65H 03/08 0 WO 99/26866 11-1998 Koch, Hans G. B65D 85/57 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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